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# EE566 Solid State Devices

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Dept of Electrical Engineering

University of Notre Dame

Instructor: Debdeep Jena ([djena@nd.edu](mailto:djena@nd.edu), x8835)

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## Assignment 5

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**Reading:** Chapters 4 & 5 of the Textbook (MS).

### **Problem 1\* (Designing the Voltage Blocking Capability of Diodes)**

Solve Problem 4.34 from the TextBook (MS).

### **Problem 2 (p-n Junction Currents – Practice Problem)**

Consider a GaAs p-n junction. The relevant parameters are  $N_d=N_a=10^{18}/\text{cm}^3$ ,  $\tau_n=\tau_p=10\text{ns}$ ,  $D_n=100\text{cm}^2/\text{s}$ ,  $D_p=20\text{cm}^2/\text{s}$ , and breakdown field  $F_{BD}=400\text{kV}/\text{cm}$ . Do the following –

- Plot the charge-field-band diagram at zero bias. Compare with a 1D Poisson simulation.
- Sketch the mobile charge (both majority and minority) density vs distance at a forward bias of 0.4 Volt.
- Sketch the electric field and the band diagram (with quasi Fermi levels) at this forward bias.
- Sketch the corresponding current densities (diffusion and drift components for both n- and p-type carriers) as a function of distance at 0.4 Volt forward bias. Find the total current density flowing across the junction.
- Repeat the above sketches for a reverse bias of -5 Volts.
- Find the reverse bias at which the p-n junction will break down.

### **Problem 3 (Current Flow in Heterojunction Diodes)**

Instead of a homojunction diode, let us see what happens if a heterojunction is used as the emitter. The doping density in a GaAs based heterostructure p-n junction is  $N_D=10^{17}/\text{cm}^3$  and  $N_A=10^{16}/\text{cm}^3$ . Design the emitter-base junction by introducing  $\text{Al}_x\text{Ga}_{1-x}\text{As}$  in the emitter layer, such that the total current in the diode improves by a factor of  $\eta=100$  than the normal GaAs p-n junction. Work out the following -

- Solve the zero-bias p-n junction problem and determine the depletion thicknesses on both sides.
- Design your emitter layer such that there are no spikes that impede the current flow. Make generous use of 1D Poisson.
- Explain why the depletion-edge in the emitter should encompass the whole change in the bandgap,  $\Delta E_G$ .
- What are the advantages of the heterojunction over the homojunction? What are the disadvantages?

### **Problem 4 (Recombination Currents in The Space-Charge Region)**

Consider a forward-biased p-n junction. Sketch the distribution of electron and hole current densities across the junction if there is significant recombination in the space-charge (depletion) region. Assume that the injected hole current is *twice* the injected electron current, and the recombination rate inside the space-charge layer is *half* the recombination rate of electrons in the p-type region.

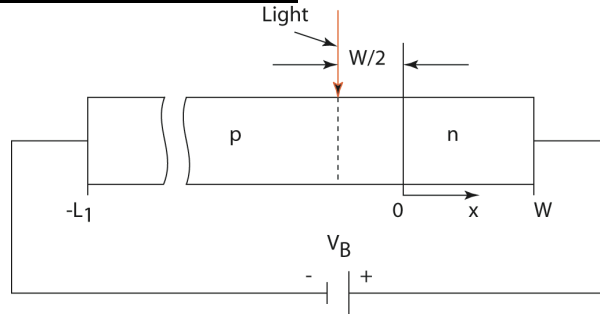
Demonstrate that the total diode current is given by adding a term that describes the space-charge recombination current to the sum of diffusion currents at the edge of the (space-charge, or) depletion region.

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\* Remember to use proper units and label every figure/plot. Turn in your answers worked out neatly. Please attach this question sheet to your solution when you turn it in.

### **Problem 5 (Generation/Recombination Currents)**



A p-n junction has the configuration as shown in the figure above. Assume the following –

- 1)  $N_a = N_d = N_0 \gg n_i$ ,
- 2)  $W \ll L$ , the minority carrier diffusion length, and  $L_1 \gg L$ .
- 3) All diffusion constants =  $D$ , all lifetimes =  $\tau$ .
- 4) The space-charge (or depletion) region thickness  $\ll W$ .
- 5) The external reverse bias is  $V_B$ , which is much larger than the built-in voltage of the p-n junction.
- 6) The *excess* minority carrier density at  $x=W$  is zero.

A beam of light is incident *on a plane of negligible width* on the p-side at a distance  $W/2$  from the junction. It produces  $G_0$  electron-hole pairs per unit area per unit time in the plane. Note the units carefully –  $G_0$  is in  $(\text{cm}^2 \cdot \text{s})^{-1}$ .

- a) Assuming low-level injection, find and sketch the minority-carrier concentrations in the neutral regions of the diode.
- b) Calculate the current that flows in the illuminated diode in terms of  $G_0$  and the diode properties.
- c) In terms of the constants associated with the diode, what current flows when the light beam is removed (in steady-state conditions)?

### **Problem 6 (Storage delays in p-n junction rectifiers)**

An ideal short-base Silicon n+-p diode has  $N_d \gg N_a$  and  $N_a = 10^{17}/\text{cm}^3$ . The width of the p-region from the edge of the depletion region to the p-contact is  $W_p = 3\mu\text{m}$ . The area of the diode is  $A = 10^{-5} \text{cm}^2$ . Assume that the n-region is degenerately doped, and use reasonable values of any constants you need.

- a) Calculate the charge stored in the neutral p-region if  $I = 0.5\text{mA}$  flows through the diode.
- b) Determine the charge stored in the narrowed depletion region under forward bias.
- c) How much time does it take a current source of  $0.5\text{mA}$  to cause the diode to switch from an off condition ( $V_a = 0$ ) to the steady state with  $0.5 \text{mA}$  of current?